



10/802,804

ATTY. DKT. 28953.7263

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Patent No. 7,141,309

Issued: November 28, 2006

Inventors: Toshiharu KINOSHITA et al

For: HIGH THERMAL CONDUCTIVE MATERIAL HAVING HIGH
THERMAL CONDUCTIVITY AND PROCESS FOR PRODUCING THE SAME

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 CFR 1.97(i)

Customer Window
U.S. Patent and Trademark Office
Randolph Building
401 Dulany St.
Alexandria, VA 22314

Sir:

Pursuant to 37 C.F.R. 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached Form PTO-1449.

The references listed on attached Form PTO-1449 include documents cited in an Office Action issued November 21, 2006 in the basic Japanese patent application. U.S. Patents Nos. 4,846,673 and 4,912,738 correspond to JP01-172290A cited in the Japanese Office Action and EP 1174400 corresponds to JP2002-11653A, as well as previously cited JP2001-158680.

Inasmuch as this IDS is being filed after issuance of the patent, it is requested that it be placed in the application file without consideration by the Office.

Respectfully submitted,

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Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 28953.7263	Patent No. 7,141,309
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant T. KINOSHITA et al	
		Filing Date March 18, 2004	Serial No. 10/802,804

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,846,673	07/1989	Tsukada	432	5	
	AB	4,913,738	04/1990	Tsukada	75	236	

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AC	2001-185665	07/2001	Japan			X	
	AD	02-7000	02/1990	Japan			Abstract	
	AE	1 174 400A	01/2002	Europe				
	AF	2002-104884	04/2002	Japan			X	
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AO	
	AP	
	AQ	
	AR	
	AS	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	